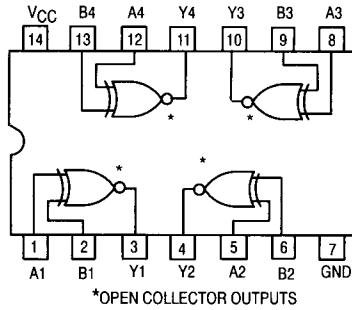




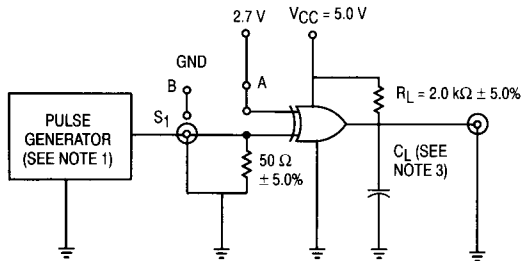
# Quad 2-Input Exclusive NOR Gate

ELECTRICALLY TESTED PER:  
MIL-M-38510/30303

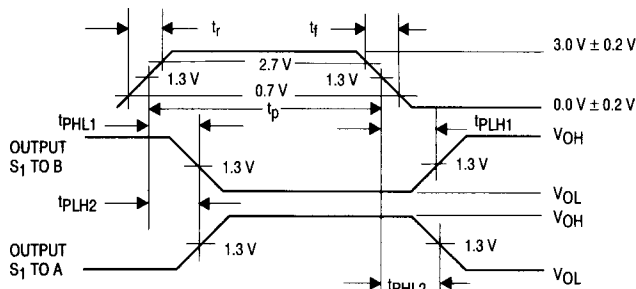
LOGIC DIAGRAM



AC TEST CIRCUIT



WAVEFORMS



**NOTES:**

- The generator has the following characteristics:  $t_r \leq 6.0$  ns,  $t_f = 15$  ns; PRR  $\leq 1.0$  MHz,  $t_p = 0.5$   $\mu$ s,  $Z_{OUT} = 50$   $\Omega$ .
- Each gate tested separately.
- $C_L = 50$  pF  $\pm 10\%$  including scope probe, wiring and stray capacitance, without package in test fixture.
- Voltage measurements are to be made with respect to network ground terminal.
- $R_L = 2.0$  k $\Omega$   $\pm 5.0\%$ .

## Military 54LS266



AVAILABLE AS:

- 1) JAN: JM38510/30303BXA
- 2) SMD: N/A
- 3) 883: 54LS266/BXAJC

X = CASE OUTLINE AS FOLLOWS:  
PACKAGE: CERDIP: C  
CERFLAT: D  
LCC: 2

THE LETTER "M" APPEARS BEFORE THE / ON LCC.

PIN ASSIGNMENTS

FUNCT.	DIL 632-08	FLATS 717-04	LCC 756A-02	BURN-IN (COND. A)
A1	1	1	2	VCC
B1	2	2	3	VCC
Y1	3	3	4	VCC
Y2	4	4	6	VCC
A2	5	5	8	VCC
B2	6	6	9	VCC
GND	7	7	10	GND
A3	8	8	12	VCC
B3	9	9	13	VCC
Y3	10	10	14	VCC
Y4	11	11	16	VCC
A4	12	12	18	VCC
B4	13	13	19	VCC
VCC	14	14	20	VCC

BURN-IN CONDITIONS:  
VCC = 5.0 V MIN/6.0 V MAX

TRUTH TABLE

Inputs		Output
A	B	Z
0	0	1
0	1	0
1	0	0
1	1	1

## 54LS266

Symbol	Parameter	Limits						Unit	Test Condition (Unless Otherwise Specified)
		+ 25°C		+ 125°C		- 55°C			
		Subgroup 1		Subgroup 2		Subgroup 3			
		Min	Max	Min	Max	Min	Max		
V <sub>OL</sub>	Logical "0" Output Voltage		0.4		0.4		0.4	V	V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 4.0 mA, V <sub>IL</sub> = 0.7 V, other input = 2.0 V, or per truth table.
V <sub>IC</sub>	Input Clamping Voltage		- 1.5					V	V <sub>CC</sub> = 4.5 V, I <sub>IN</sub> = - 18 mA, other input is open.
I <sub>CEX</sub>	Open Collector Input Current		100		100		100	μA	V <sub>CC</sub> = 4.5 V, V <sub>OUT</sub> = 5.5 V, V <sub>IL</sub> = 0.7 V, other input = 0.7 V, or per truth table.
I <sub>IH</sub>	Logical "1" Input Current		40		40		40	μA	V <sub>CC</sub> = 5.5 V, V <sub>IH</sub> = 2.7 V, other input = GND.
I <sub>IHH</sub>	Logical "1" Input Current		200		200		200	μA	V <sub>CC</sub> = 5.5 V, V <sub>IHH</sub> = 5.5 V, other input = GND.
I <sub>IL</sub>	Logical "0" Input Current	- 300	- 760	- 300	- 760	- 300	- 760	μA	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 0.4 V, other input = 5.5 V.
I <sub>CC</sub>	Power Supply Current		13		13		13	mA	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 4.5 V, other input = GND.
V <sub>IH</sub>	Logical "1" Input Voltage	2.0		2.0		2.0		V	V <sub>CC</sub> = 4.5 V.
V <sub>IL</sub>	Logical "0" Input Voltage		0.7		0.7		0.7	V	V <sub>CC</sub> = 4.5 V.
	Functional Tests	Subgroup 7		Subgroup 8A		Subgroup 8B			per Truth Table with V <sub>CC</sub> = 5.0 V, V <sub>INL</sub> = 0.4 V, and V <sub>INH</sub> = 2.5 V.

Symbol	Parameter	Limits						Unit	Test Condition (Unless Otherwise Specified)
		+ 25°C		+ 125°C		- 55°C			
		Subgroup 9		Subgroup 10		Subgroup 11			
		Min	Max	Min	Max	Min	Max		
t <sub>PHL1</sub> t <sub>PHL1</sub>	Propagation Delay /Data-Output Output High-Low	2.0 —	40 30	2.0 —	45 40	2.0 —	45 40	ns	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2.0 kΩ
t <sub>PLH1</sub> t <sub>PLH1</sub>	Propagation Delay /Data-Output Output Low-High	2.0 —	45 30	2.0 —	56 51	2.0 —	56 51	ns	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2.0 kΩ
t <sub>PHL2</sub> t <sub>PHL2</sub>	Propagation Delay /Data-Output Output Low-High	2.0 —	40 30	2.0 —	45 40	2.0 —	45 40	ns	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2.0 kΩ
t <sub>PLH2</sub> t <sub>PLH2</sub>	Propagation Delay /Data-Output Output Low-High	2.0 —	45 30	2.0 —	56 51	2.0 —	56 51	ns	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 2.0 kΩ V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2.0 kΩ

**NOTE:**

- The limits specified for C<sub>L</sub> = 15 pF are guaranteed but not tested.